MN74HC266/MN74HC266S

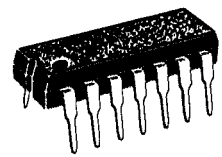
Quad 2-Input Exclusive NOR Gates

■ Outline

The MN74HC266/MN74HC266S is constituted by 2-input exclusive NOR gates having four built-in circuis in one chip. Owing to the silicon gate CMOS process, these NOR gates have realized low power consumption and high noise immunity equivalent to those of a standard CMOS and the operation speed as high as of an LS TTL. The respective output can directly drive ten LS TTL inputs.

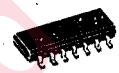
To protect the input and output against electrostatic breakdown, a resistor and a diode are used for the V_{CC} and the GND. The pin configuration and the function are the same as those of the standard 54LS/74LS logic family.

P-1



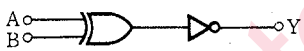
14-pin plastic DIL package

P-2

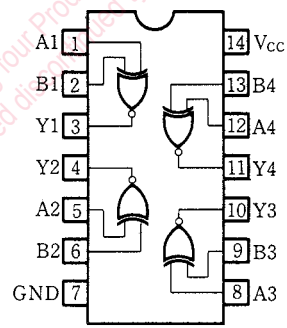


14-pin PANAFLAT package (SO-14D)

■ Logic Diagram (1 Gate)



Pin Configuration



■ Absolute Maximum Ratings

Item			Symbol	Rating	Unit
Supply voltage			V_{CC}	−0.5~+7.0	V
Input output voltage			V_I, V_O	−0.5~V_{CC}+0.5	V
Input protective diode current			I_{IK}	±20	mA
Output parasitic diode current			I_{OK}	±20	mA
Output current			I_O	±25	mA
Supply current			I_{CC}, I_{GND}	±50	mA
Storage temperature			T_{stg}	−65~+150	°C
Power dissipation	MN74HC266	Ta=−40~+60°C	P_D	400	mW
		Ta=+60~+85°C		Decrease to 200mW at the rate of 8mW/°C	
	MN74HC266S	Ta=−40~+60°C	P_D	275	mW
		Ta=+60~+85°C		Decrease to 200mW at the rate of 3.8mW/°C	

■ Recommended Operating Conditions

Item	Symbol	V_{CC}(V)	Rating	Unit
Operating power supply voltage	V_{CC}		1.4~6.0	V
Input output voltage	V_I, V_O		0~V_{CC}	V
Operating temperature	T_A		−40~+85	°C
Input rise, fall time	t_r, t_f	2.0	0~1000	ns
		4.5	0~500	ns
		6.0	0~400	ns

■ DC Characteristics (GND=0V)

Item	Symbol	V_{CC} (V)	Test Condition V_I	Test Condition I_O	Test Condition Unit	Ta=25°C min.	Ta=25°C typ.	Ta=25°C max.	Ta=−40~+85°C min.	Ta=−40~+85°C max.	Unit
Input voltage high level	V_{IH}	2.0				1.5			1.5		V
		4.5				3.15			3.15		
		6.0				4.2			4.2		
Input voltage low level	V_{IL}	2.0						0.3		0.3	V
		4.5						0.9		0.9	
		6.0						1.2		1.2	
Output voltage high level	V_{OH}	2.0	V_{IH} or V_{IL}	−20.0	μA	1.9	2.0		1.9		V
		4.5		−20.0	μA	4.4	4.5		4.4		
		6.0		−20.0	μA	5.9	6.0		5.9		
		4.5		−4.0	mA	3.92			3.84		
		6.0		−5.2	mA	5.48			5.34		
Output voltage low level	V_{OL}	2.0	V_{IH} or V_{IL}	20.0	μA		0.0	0.1		0.1	V
		4.5		20.0	μA		0.0	0.1		0.1	
		6.0		20.0	μA		0.0	0.1		0.1	
		4.5		4.0	mA			0.26		0.33	
		6.0		5.2	mA			0.26		0.33	
Input leakage current	I_I	6.0	V_I=V_{CC} or GND					±0.1		±1.0	μA
Static supply current	I_{CC}	6.0	V_I=V_{CC} or GND, I_O=0					2.0		20.0	μA

■ AC Characteristics (GND=0V, Input transition time≦6ns, C_L=50pF)

Item	Symbol	V_{CC} (V)	Test Condition	Ta=25°C min.	Ta=25°C typ.	Ta=25°C max.	Ta=−40~+85°C min.	Ta=−40~+85°C max.	Unit
Output rise time	t_{TLH}	2.0			25	75		95	ns
		4.5			8	15		19	
		6.0			7	13		16	
Output fall time	t_{THL}	2.0			20	75		95	ns
		4.5			7	15		19	
		6.0			6	13		16	
Propagation time (L→H)	t_{PLH}	2.0			25	75		95	ns
		4.5			8	15		19	
		6.0			7	13		16	
Propagation time (H→L)	t_{PHL}	2.0			25	75		95	ns
		4.5			8	15		19	
		6.0			7	13		16	

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